5 8 by A	U.S. Department of Commerce Patent and Trademark Office sclosure Statement Applicant sheets if necessary)	Attorney's Docket No. 10559-927001	Application No. 10/824,305	
		Applicant Richard Schenker		
		Filing Date April 13, 2004	Group Art Unit 2873	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication - Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD					•	
	AE						
	AF						
	AG						
	AH						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AI						·	
	AJ							
·	AK							
	AŁ		-	·				
	· AM							

Other Documents (include Author, Title, Date, and Place of Publication)				
Examiner Initial	Desig. ID	Document		
ن.د	AN	Konstantinos Adam et al., "Polarization Effects in Immersion Lithography", Optical Mecrolithography XVII, Proceedings of SPIE Vol. 5377, pgs. 329-343, 2004		
٠.(	AO	Richard Schenker et al., "Material Limitations to 193-nm Lithographic System Lifetimes", SPIE Vol. 2726, pgs. 698-706		
ت. د	ΑP	Richard E. Schenker et al., "Ultraviolet-induced densification in fused silica", J. Appl. Phys. 82 (3), August 1, 1997, pgs. 1065-1071		
ن . ر ،	AQ	G. de Zwart et al., "Performance of a Step and Scan System for DUV Lithography", SPIE Vol. 3051, pgs. 817-830		
w·c	AR	U.S. Patent Application Serial No. 10/813,453, filed March 29, 2004, "LITHOGRAPHY USING CONTROLLED POLARIZATION"		

Examiner Signature	Date Considered 6/3/06.				
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					